

Substitute for form 1449A/PTO

Complete if Known

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Use as many sheets as necessary)

Application Number	10/607,769
Filing Date	June 27, 2003
First Named Inventor	Hareland, Scott A.
Group Art Unit	2891
Examiner Name	Such, Matthew W.

Sheet 1 of 7

Attorney Docket No: 42P15685

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Based on PTO/BD/909-06; Substitute Disclosure Statement Form (PTO-1449) as modified by 8572 03/26/07

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	Group Art Unit	2891
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Sheet 2 of 7	Attorney Docket No: 42P15685	

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OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Sheet 7 of 7	Attorney Docket No: 42P15685	

/MWS/		TOKORO, KENJI , et al., "Anisotropic Etching Properties of Silicon in KOH and TMAH Solutions", International Symposium on Micromechatronics and Human Science, IEEE, (1998), pp. 65-70	
/MWS/		WOLF, STANLEY , et al., "Wet Etching Silicon", Silicon Processing for the VLSI Era, Vol. 1: Process Technology, Lattice Press, Sunset Beach, CA, (Sept. 1986), 3 pages	

EXAMINER

/Matthew Such/

DATE CONSIDERED

07/20/2008

Based on PTO/SB96A(09-09), Substitute Disclosure Statement Form (PTO-1449) as modified by BSTZ 032607
 * EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 009. Draw line through citation if not in conformance and not considered. Includes copy of this form with next communication to applicant. Applicant's unique citation designation number (optional) : Applicant is to place a check mark here if English language Translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /MWS/